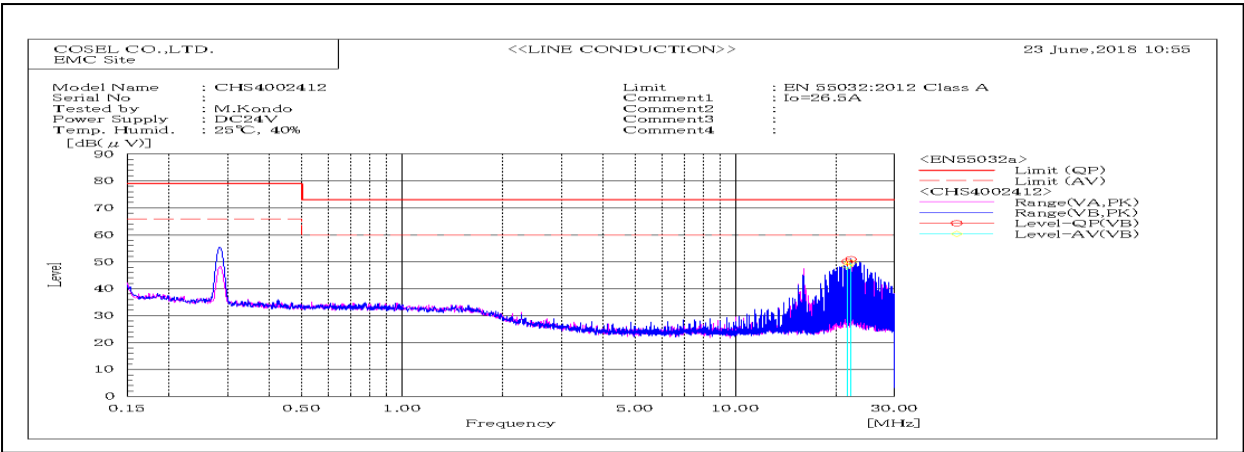
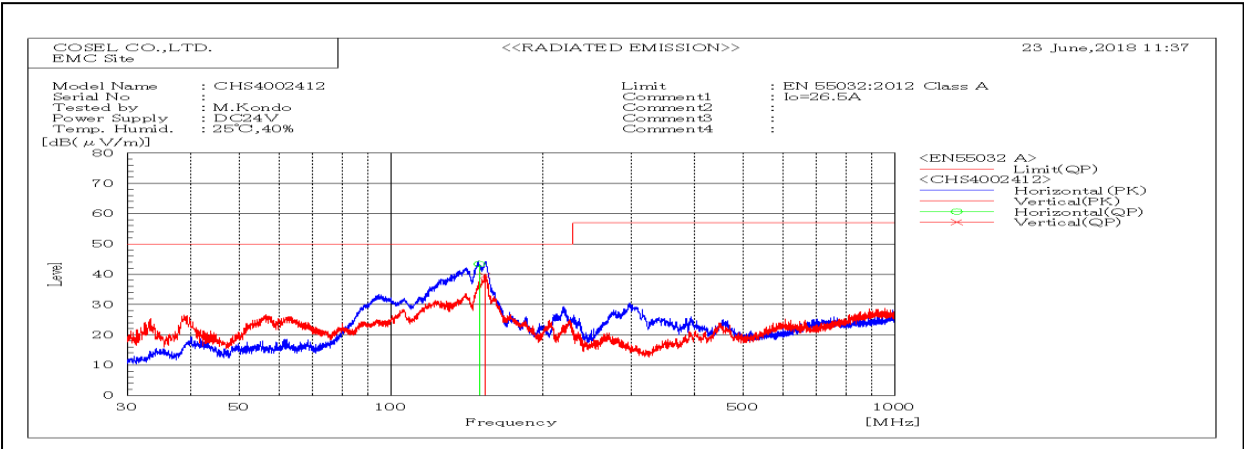


DATA SHEET		Date	26-Jun-18
Model	CHS4002412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo



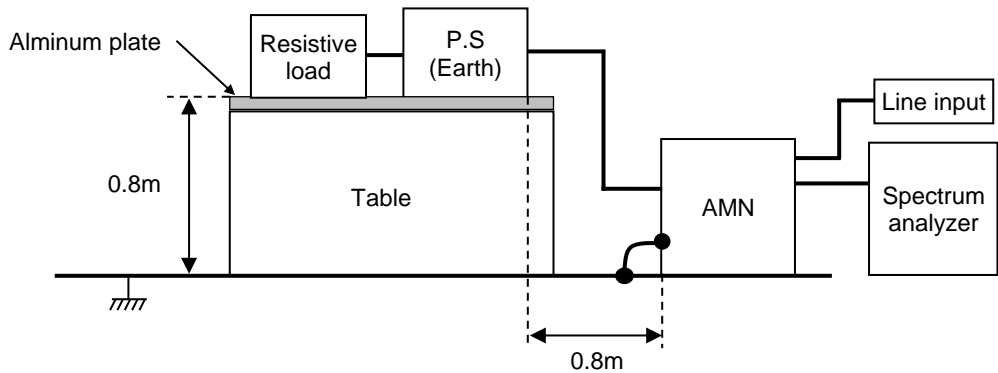
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
21.611	VB	50	48.4	73	60	23	11.6	Pass	
22.1666	VB	50.9	49.7	73	60	22.1	10.3	Pass	



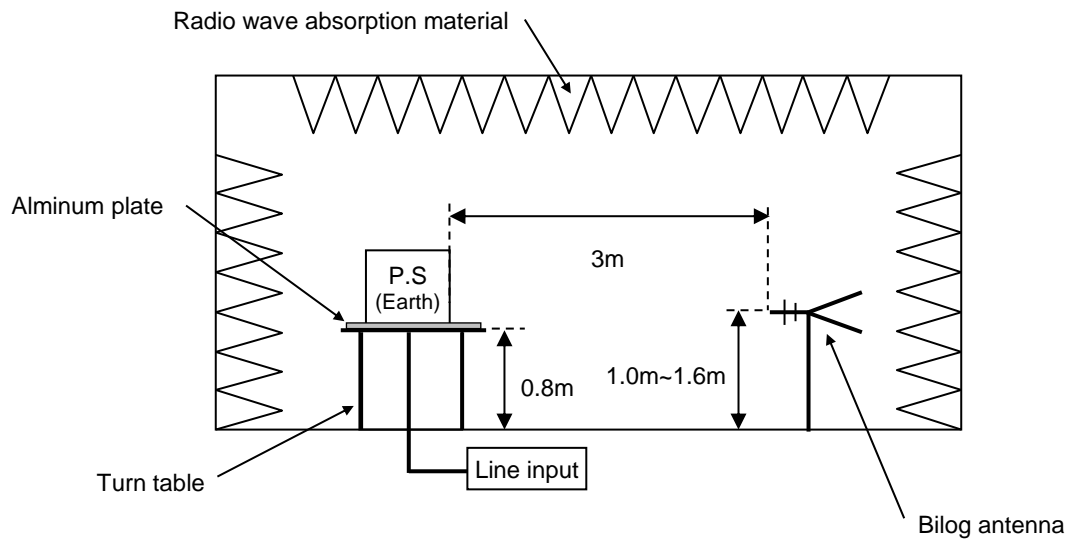
Frequency MHz	Polariz ation	Stabilit y	Reading dB(uV)	Limit dB(uV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
149.871	H	Stable	56.8	50	6.6	Pass	185	221	
153.831	V	Stable	55.2	50	10.4	Pass	100	278	

DATA SHEET		Date	26-Jun-18
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : CHS40024□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

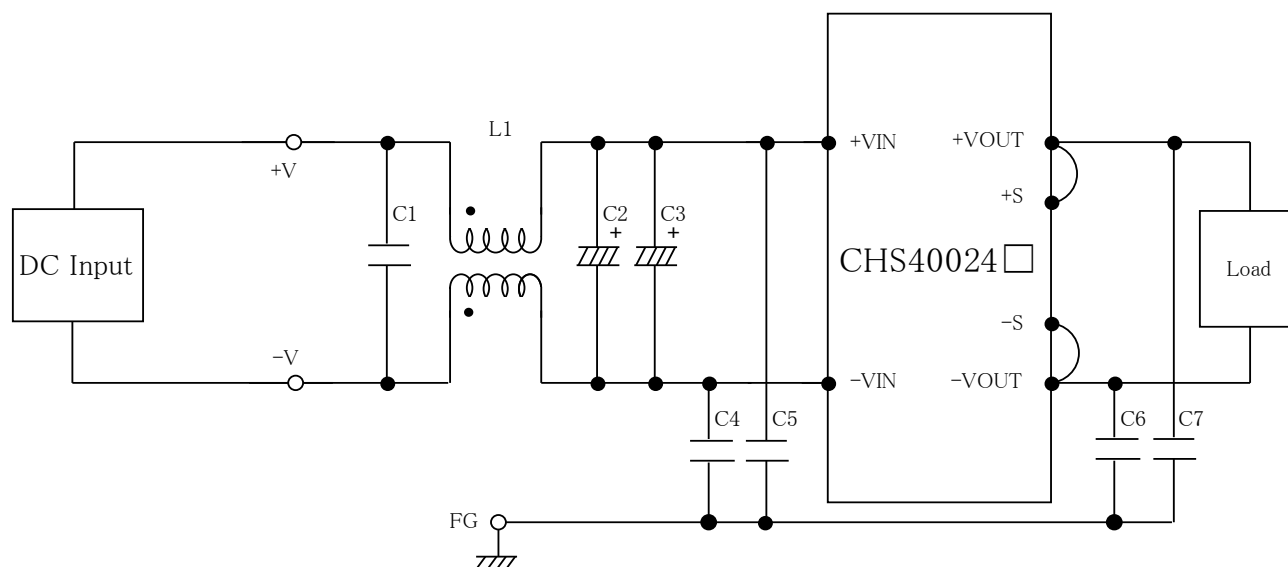


Fig.1 Testing circuitry

L1 : 1mH SC-30-100 (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C3 : 50V 330 μ F PWseries (nichicon)
C4,C5 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C6,C7 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)